

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/766,050	MORADMAND ET AL.	
Examiner Christopher P. Schwartz		Art Unit 3683	Page 1 of 2	

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-3614267			
B	US-4475870			
C	US-4721346			
D	US-4840544			
E	US-5078458			
F	US-5383718			
G	US-5927824			
H	US-us005992944a			
I	US-us006074018a			
J	US-us006168245b1			
K	US-us006199962b1			
L	US-us006234588b1			
M	US-us006286914b1			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
U			
V			
W			
X			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited			Application/Control No. 10/766,050	Applicant(s)/Patent Under Reexamination MORADMAND ET AL.	
			Examiner Christopher P. Schwartz	Art Unit 3683	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,386,842 b1	05-2002	Reuter et al.	417/417
	B	US-6,648,614 b1	11-2003	Hinz et al.	417/470
	C	US-6,817,838 b2	11-2004	Mori, Katsumi	417/244
	D	US-2003/0234574 a1	12-2003	Reuter et al.	303/116.2
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.